

Description

The HXY5N50D can be used in various power swithching circuit for system miniaturization and higher efficiency. The package form is TO-252-2L, which accords with the RoHS standard.

General Features

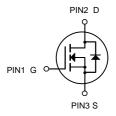
 $V_{DS} = 500 \text{ V}, I_D = 5\text{A}$ $R_{DS(ON)} < 1.8 \Omega \text{@ } V_{GS} = 10\text{V}$

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TO-252-2L

Application

• Power switch circuit of adaptor and charger.



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
HXY5N50D	TO252-2L	5N50 XXX YYYY	2500

Absolute Maximum Ratings@T_j=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	500	٧
VGS	Gate-Source Voltage	<u>+</u> 30	V
I _D @T _C =25°C	Drain Current, V _{GS} @ 4.5V	5	Α
I _D @T _C =100°C	Drain Current, V _{GS} @ 4.5V	2.6	А
IDM	Pulsed Drain Current ¹	20	Α
P _D @T _C =25°C	Total Power Dissipation	24.5	W
Eas	Single Pulse Avalanche Energy ⁴	167	mJ
TSTG	Storage Temperature Range	-55 to 150	℃
TJ	Operating Junction Temperature Range	-55 to 150	°C



Electrical Characteristics (Tc= 25°C unless otherwise specified):

BVDSS Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ 500 ΔBVDSS Breakdown Voltage Temperature $I_D = 250 \text{ μA}$, Referenced to 25°C 0.49 IDSS Zero Gate Voltage Drain Current $V_{DS} = 500 \text{ V}$, $V_{GS} = 0 \text{ V}$ $V_{DS} = 400 \text{ V}$, $V_{CS} = 125 \text{ C}$ IGSSF Gate-Body Leakage Current, Forward $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ IGSSR Gate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}$, $V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS}(TH)$ Gate Threshold voltage $V_{DS} = V_{GS}$, $I_D = 250 \text{ uA}$ 2.0 $V_{GS} = 10 \text{ V}$, $I_D = 2A$,	Max	Units
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		V
$V_{DS} = 400 \text{ V, TC} = 125^{\circ}\text{C}$ $I_{GSSF} \qquad \text{Gate-Body Leakage Current, Forward} \qquad V_{GS} = 30 \text{ V, } V_{DS} = 0 \text{ V}$ $I_{GSSR} \qquad \text{Gate-Body Leakage Current, Reverse} \qquad V_{GS} = -30 \text{ V, } V_{DS} = 0 \text{ V}$ $\text{On Characteristics}$ $V_{GS(TH)} \qquad \text{Gate Threshold voltage} \qquad V_{DS} = V_{GS}, I_{D} = 250 \text{ uA} \qquad 2.0$		V/°C
$I_{GSSF} \qquad \text{Gate-Body Leakage Current, Forward} \qquad V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ $I_{GSSR} \qquad \text{Gate-Body Leakage Current, Reverse} \qquad V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ $\text{On Characteristics}$ $V_{GS(TH)} \qquad \text{Gate Threshold voltage} \qquad V_{DS} = V_{GS}, I_{D} = 250 \text{ uA} \qquad 2.0$	1	μA
I_{GSSR} Gate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS(TH)}$ Gate Threshold voltage $V_{DS} = V_{GS}, I_D = 250 \text{ uA}$ 2.0	10	μA
I_{GSSR} Gate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS(TH)}$ Gate Threshold voltage $V_{DS} = V_{GS}, I_{D} = 250 \text{ uA}$ 2.0	100	nA
$V_{GS(TH)}$ Gate Threshold voltage $V_{DS}=V_{GS}$, $I_D=250$ uA 2.0	-100	nA
407/1		
V -10 V I - 2A T -	4.0	V
$R_{DS(On)}$ Drain-Source on-state resistance $V_{GS}=10 \text{ V}, I_D=2A, I_J=25 \text{ C}$ 1.49 $V_{DS}=40 \text{ V}, I_D=2.5 \text{ A}$	1.8	Ω
g_{FS} Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 2.5 \text{ A}$ (Note 4)		S
Dynamic Characteristics		
C _{iss} Input capacitance 415		pF
$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f}$ Output capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f}$ $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f}$ $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f}$		pF
C _{rss} Reverse transfer capacitance 1.4		pF
Switching Characteristics		
t _{d(on)} Turn On Delay Time 7		ns
t_r Rising Time $V_{DD} = 250 \text{ V, ID} = 5 \text{ A,}$ 22		ns
$t_{d(off)} \qquad \text{Turn Off Delay Time} \qquad \qquad R_G = 25 \ \Omega \\ \text{(Note 4, 5)} \qquad \qquad 15 \ \Omega$		ns
t _f Fall Time 23		ns
Q _g Total Gate Charge		nC
Q_{gs} Gate-Source Charge $V_{DS} = 400 \text{ V}, \text{ ID} = 5 \text{ A}, V_{GS} = 10 \text{ V}$ 4.9		nC
Q _{gd} Gate-Drain Charge (Note 4, 5)		nC
Drain-source Diode Characteristics and Maximum Ratings	•	
I _S Maximum continuous Drain-source Diode Forward Current	5	А
I _{SM} Maximum Pulsed Drain-Source Diode Forward Current	20	А
V _{SD} Diode Forward Voltage V _{GS} = 0 V, I _S = 5 A	1.2	V
t_{rr} Reverse Recovery Time $V_{GS} = 0 \text{ V}, I_S = 5 \text{ A},$ 289		ns
Q_{rr} Reverse Recovery Charge $dl_F/dt = 100 \text{ A/}\mu\text{s}$ $dl_F/dt = 100 \text{ A/}\mu$		-

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 10.6 mH, IAS = 5 A, VDD = 50V, RG = 25 Ω, Starting TJ = 25° C
- 3. ISD≤5A, di/dt ≤200A/us, VDD ≤ BVDSS, Starting TJ = 25°C 4. Pulse Test : Pulse width ≤ 300us, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

Table 7 Reverse diode characteristics

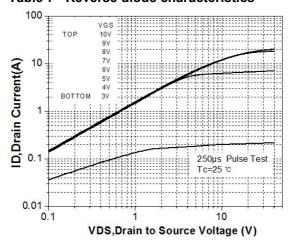


Figure 1. On-Region Characteristics

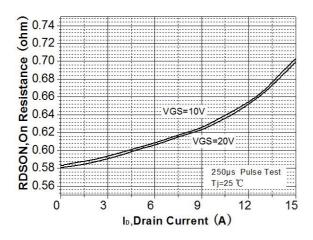


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

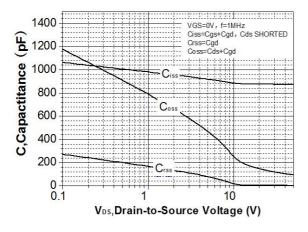


Figure 5. Capacitance Characteristics

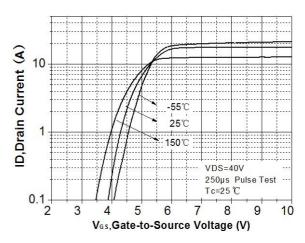


Figure 2. Transfer Characteristics

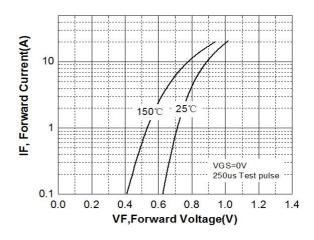


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

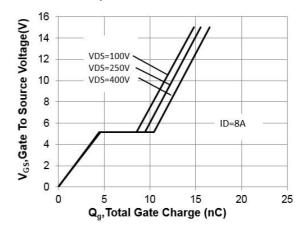


Figure 6. Gate Charge Characteristics

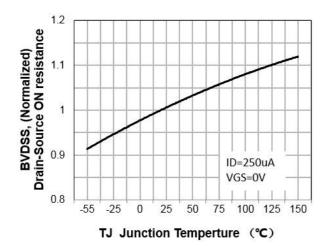


Figure 7. Breakdown Voltage Variation vs Temperature

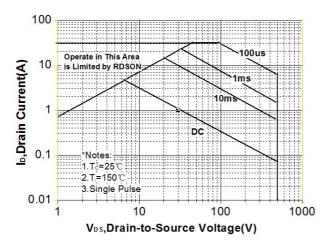


Figure 9. Maximum Safe Operating Area

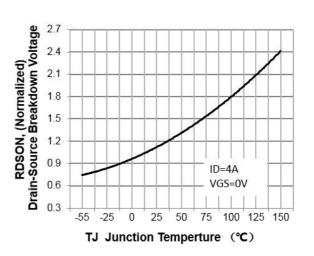


Figure 8. On-Resistance Variation vs Temperature

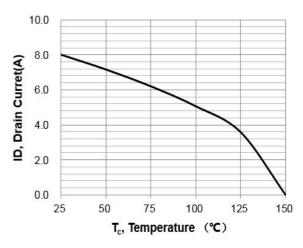
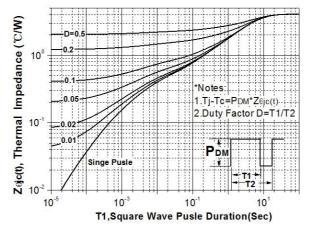
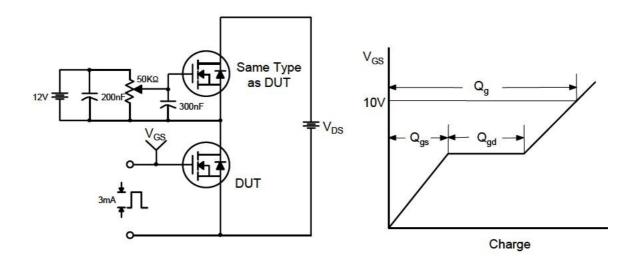


Figure 10. Maximum Drain Current vs Case Temperature Figure

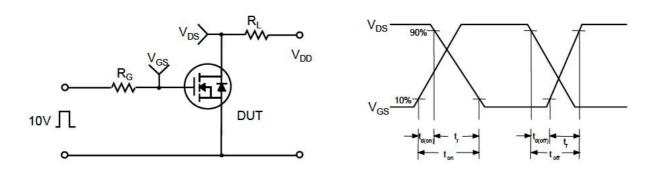


11. Transient Thermal Response Curve

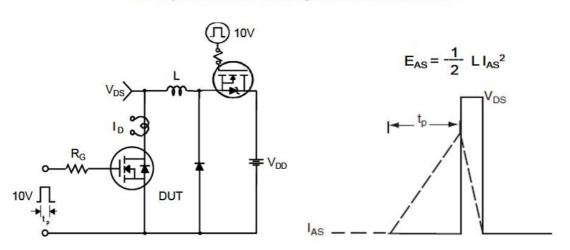
Gate Charge Test Circuit & Waveform



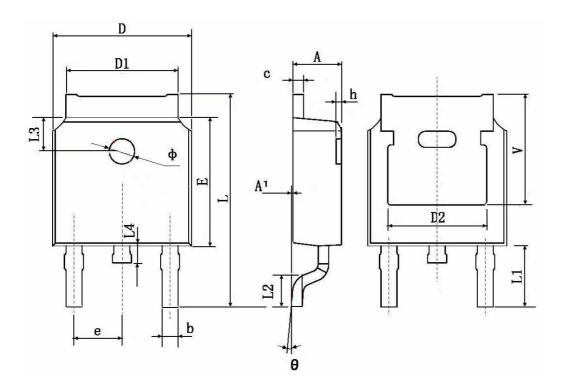
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



TO252-2L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
Е	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	



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